



FQP27P06

P-Channel QFET® MOSFET

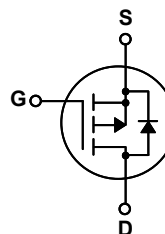
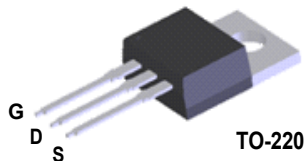
- 60 V, - 27 A, 70 mΩ

Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- - 27 A, - 60 V, $R_{DS(on)} = 70 \text{ m}\Omega$ (Max.) @ $V_{GS} = - 10 \text{ V}$, $I_D = - 13.5 \text{ A}$
- Low Gate Charge (Typ. 33 nC)
- Low C_{rss} (Typ. 120 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | FQP27P06 | Unit |
|----------------|---|-------------|------|
| V_{DSS} | Drain-Source Voltage | -60 | V |
| I_D | Drain Current - Continuous ($T_C = 25^\circ\text{C}$) | -27 | A |
| | - Continuous ($T_C = 100^\circ\text{C}$) | -19.1 | A |
| I_{DM} | Drain Current - Pulsed (Note 1) | -108 | A |
| V_{GSS} | Gate-Source Voltage | ± 25 | V |
| E_{AS} | Single Pulsed Avalanche Energy (Note 2) | 560 | mJ |
| I_{AR} | Avalanche Current (Note 1) | -27 | A |
| E_{AR} | Repetitive Avalanche Energy (Note 1) | 12 | mJ |
| dv/dt | Peak Diode Recovery dv/dt (Note 3) | -7.0 | V/ns |
| P_D | Power Dissipation ($T_C = 25^\circ\text{C}$) | 120 | W |
| | - Derate above 25°C | 0.8 | W/°C |
| T_J, T_{STG} | Operating and Storage Temperature Range | -55 to +175 | °C |
| T_L | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | 300 | °C |

Thermal Characteristics

| Symbol | Parameter | FQP27P06 | Unit |
|-----------------|---|----------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case, Max. | 1.25 | °C/W |
| $R_{\theta CS}$ | Thermal Resistance, Case-to-Sink, Typ. | 0.5 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient, Max. | 62.5 | °C/W |

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
|---|---|--|----------|-------|------|---------------------|
| Off Characteristics | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$ | -60 | -- | -- | V |
| $\Delta BV_{DSS} / \Delta T_J$ | Breakdown Voltage Temperature Coefficient | $I_D = -250\ \mu\text{A}$, Referenced to 25°C | -- | -0.06 | -- | V/ $^\circ\text{C}$ |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -60\text{ V}, V_{GS} = 0\text{ V}$ | -- | -- | -1 | μA |
| | | $V_{DS} = -48\text{ V}, T_C = 150^\circ\text{C}$ | -- | -- | -10 | μA |
| I_{GSSF} | Gate-Body Leakage Current, Forward | $V_{GS} = -25\text{ V}, V_{DS} = 0\text{ V}$ | -- | -- | -100 | nA |
| I_{GSSR} | Gate-Body Leakage Current, Reverse | $V_{GS} = 25\text{ V}, V_{DS} = 0\text{ V}$ | -- | -- | 100 | nA |
| On Characteristics | | | | | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$ | -2.0 | -- | -4.0 | V |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS} = -10\text{ V}, I_D = -13.5\text{ A}$ | -- | 0.055 | 0.07 | Ω |
| g_{FS} | Forward Transconductance | $V_{DS} = -30\text{ V}, I_D = -13.5\text{ A}$ | -- | 12.4 | -- | S |
| Dynamic Characteristics | | | | | | |
| C_{iss} | Input Capacitance | $V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$ | -- | 1100 | 1400 | pF |
| C_{oss} | Output Capacitance | | -- | 510 | 660 | pF |
| C_{riss} | Reverse Transfer Capacitance | | -- | 120 | 155 | pF |
| Switching Characteristics | | | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | $V_{DD} = -30\text{ V}, I_D = -13.5\text{ A},$ $R_G = 25\ \Omega$ | -- | 18 | 45 | ns |
| t_r | Turn-On Rise Time | | -- | 185 | 380 | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | | -- | 30 | 70 | ns |
| t_f | Turn-Off Fall Time | | (Note 4) | -- | 90 | 190 |
| Q_g | Total Gate Charge | $V_{DS} = -48\text{ V}, I_D = -27\text{ A},$ $V_{GS} = -10\text{ V}$ | -- | 33 | 43 | nC |
| Q_{gs} | Gate-Source Charge | | -- | 6.8 | -- | nC |
| Q_{gd} | Gate-Drain Charge | | (Note 4) | -- | 18 | -- |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| I_S | Maximum Continuous Drain-Source Diode Forward Current | | -- | -- | -27 | A |
| I_{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | -- | -- | -108 | A |
| V_{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0\text{ V}, I_S = -27\text{ A}$ | -- | -- | -4.0 | V |
| t_{rr} | Reverse Recovery Time | $V_{GS} = 0\text{ V}, I_S = -27\text{ A},$ $di_F / dt = 100\text{ A}/\mu\text{s}$ | -- | 105 | -- | ns |
| Q_{rr} | Reverse Recovery Charge | | -- | 0.41 | -- | μC |

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 0.9\text{ mH}, I_{AS} = -27\text{ A}, V_{DD} = -25\text{ V}, R_G = 25\ \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq -27\text{ A}, di/dt \leq 300\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Essentially independent of operating temperature

Typical Characteristics

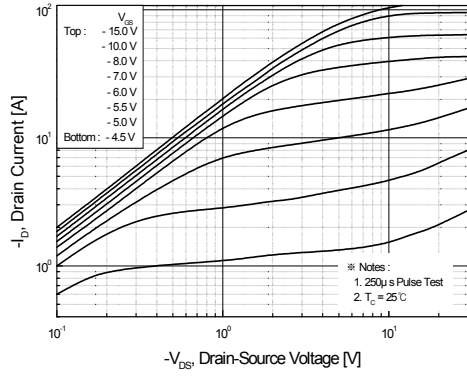


Figure 1. On-Region Characteristics

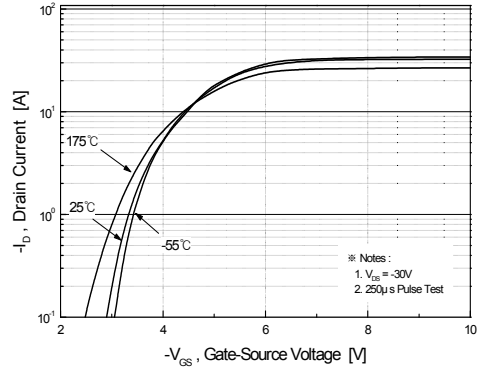


Figure 2. Transfer Characteristics

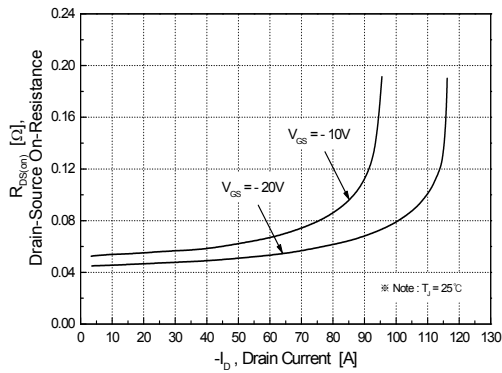


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

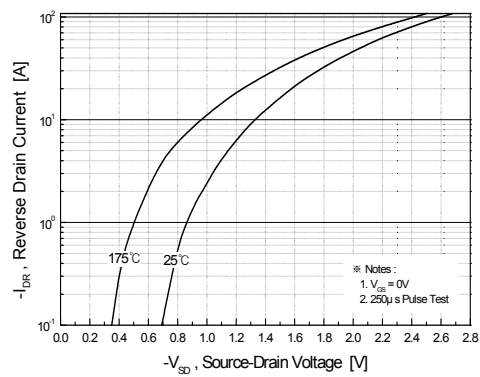


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

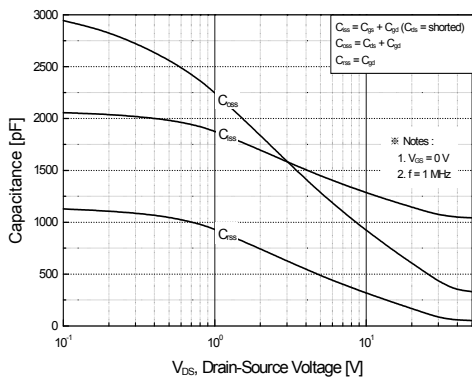


Figure 5. Capacitance Characteristics

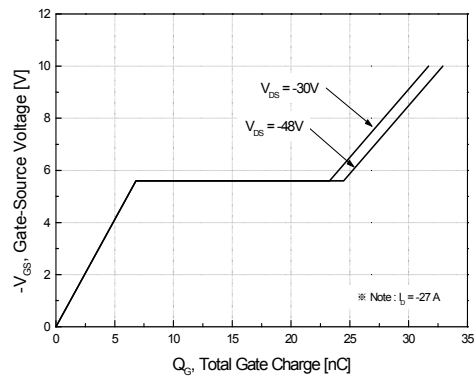


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

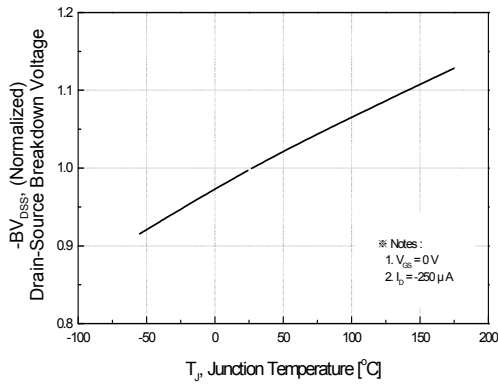


Figure 7. Breakdown Voltage Variation vs. Temperature

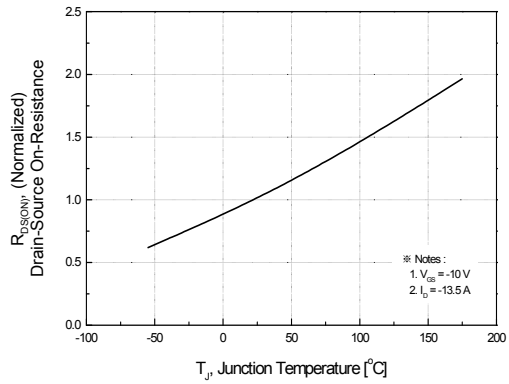


Figure 8. On-Resistance Variation vs. Temperature

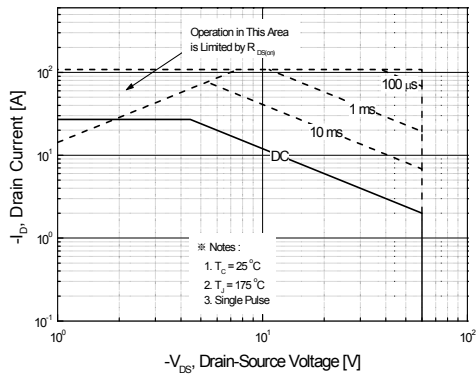


Figure 9. Maximum Safe Operating Area

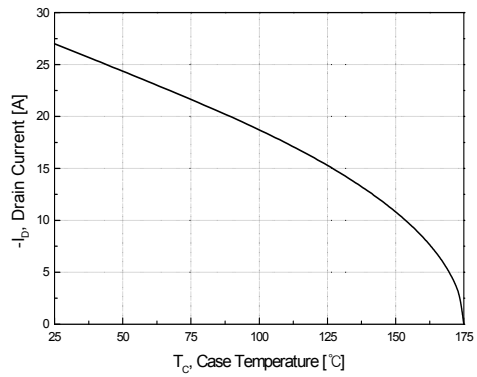


Figure 10. Maximum Drain Current vs. Case Temperature

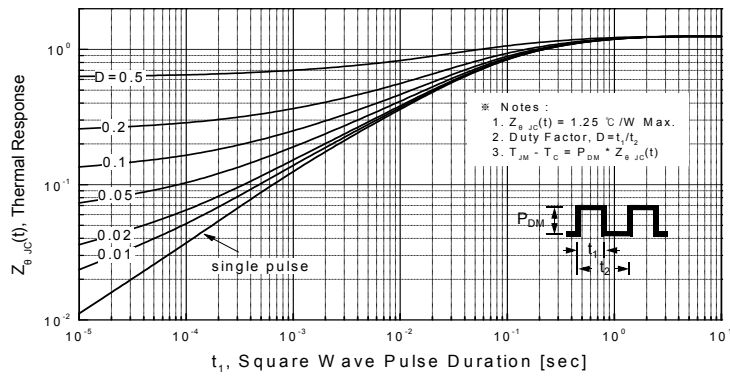
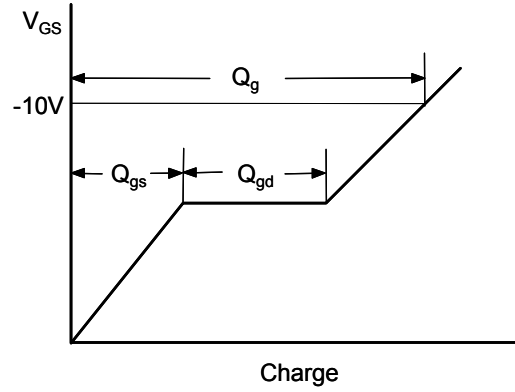
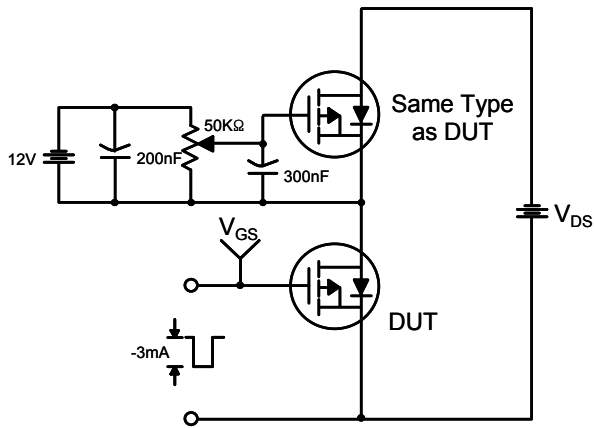
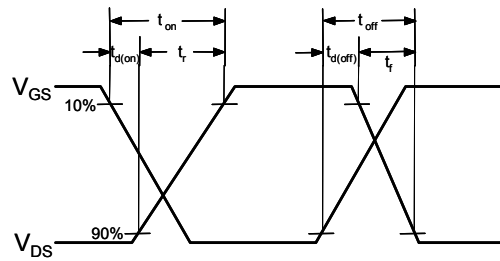
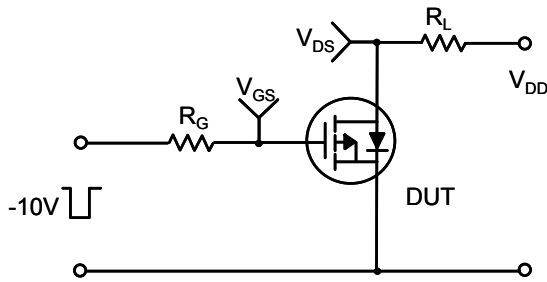


Figure 11. Transient Thermal Response Curve

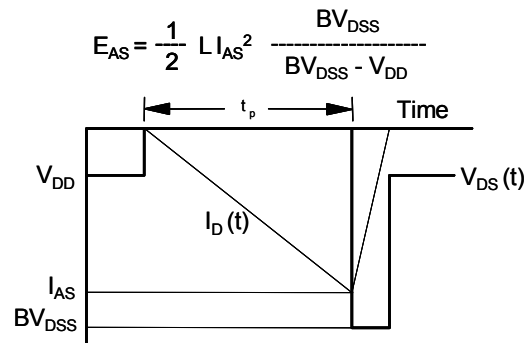
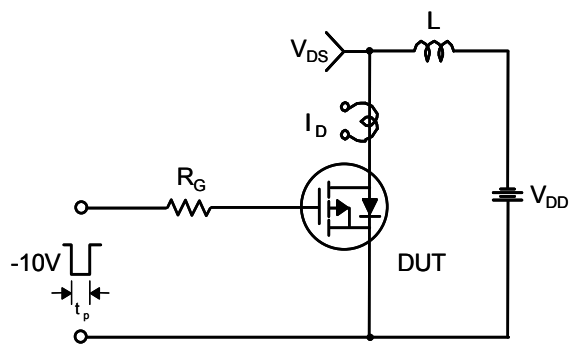
Gate Charge Test Circuit & Waveform



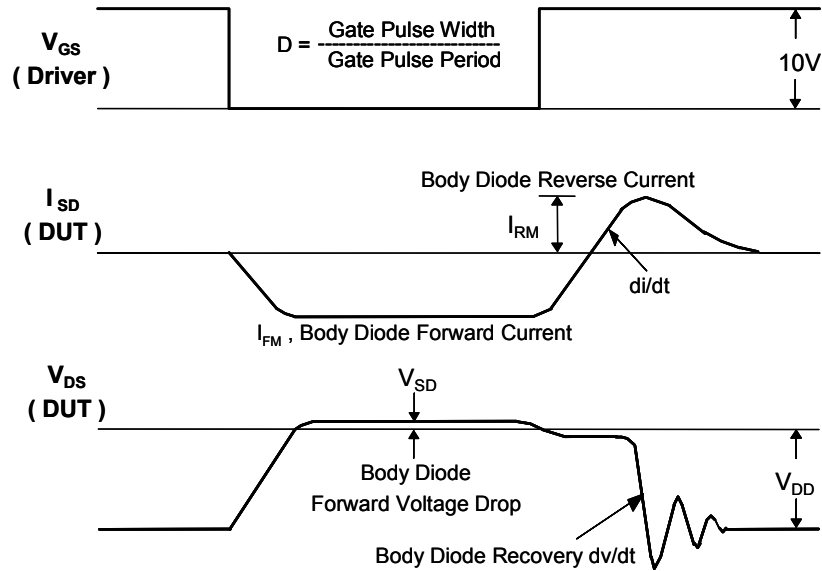
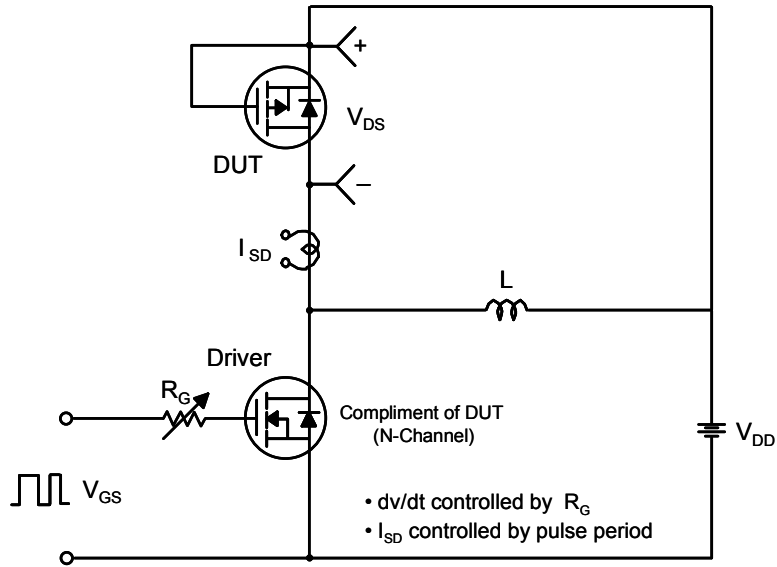
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

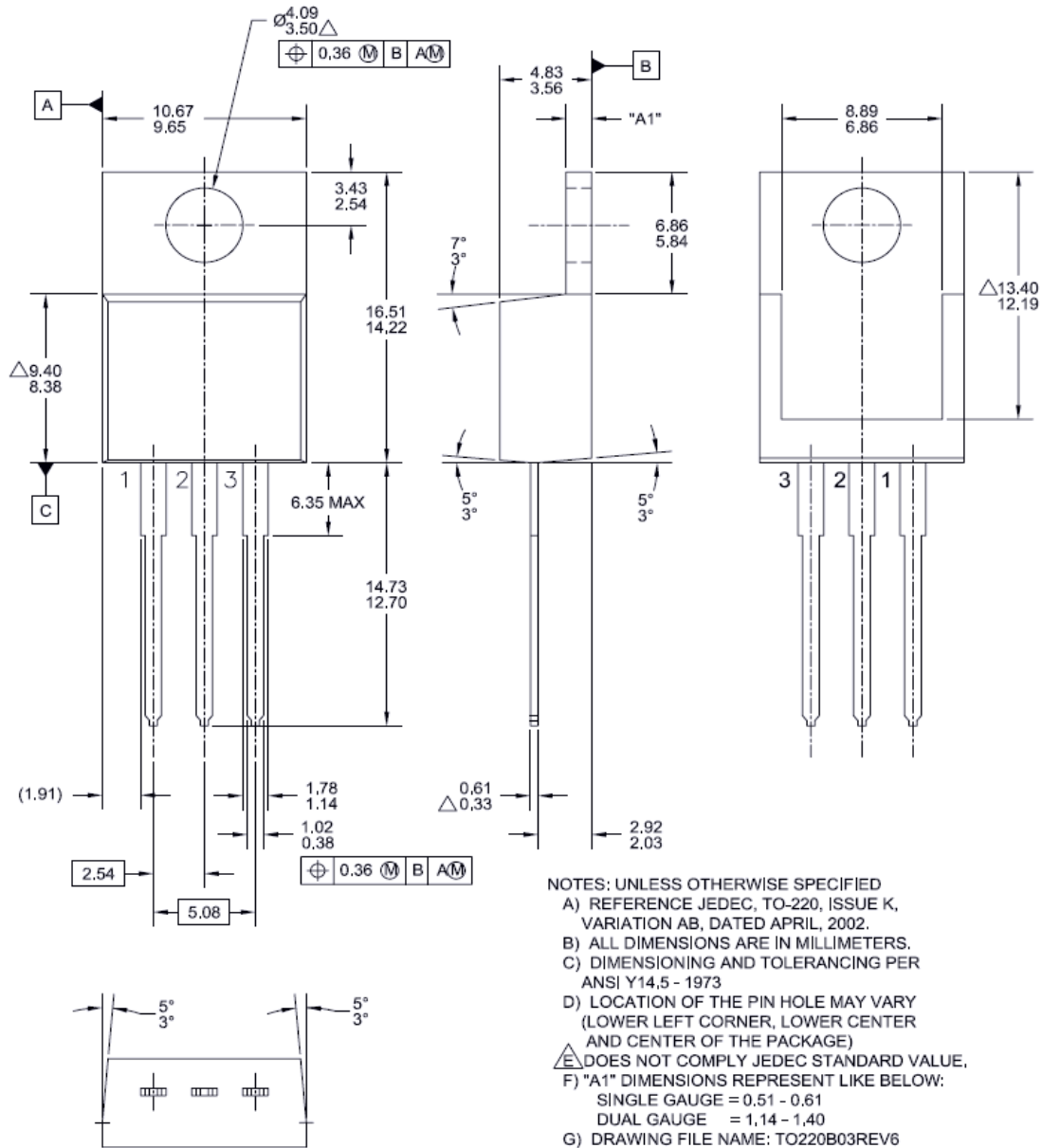


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimensions

TO-220








- NOTES: UNLESS OTHERWISE SPECIFIED
- A) REFERENCE JEDEC, TO-220, ISSUE K, VARIATION AB, DATED APRIL, 2002.
 - B) ALL DIMENSIONS ARE IN MILLIMETERS.
 - C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5 - 1973
 - D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE)
 - E) Δ DOES NOT COMPLY JEDEC STANDARD VALUE.
 - F) "A1" DIMENSIONS REPRESENT LIKE BELOW:
SINGLE GAUGE = 0.51 - 0.61
DUAL GAUGE = 1.14 - 1.40
 - G) DRAWING FILE NAME: TO220B03REV6

FQP27P06 P-Channel QFET[®] MOSFET



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